

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Semiconductor devices – Mechanical and climatic test methods –
Part 23: High temperature operating life**

**Dispositifs à semiconducteurs – Méthodes d'essais mécaniques et climatiques –
Partie 23: Durée de vie en fonctionnement à haute température**





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IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland
Email: inmail@iec.ch
Web: www.iec.ch

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Tél.: +41 22 919 02 11
Fax: +41 22 919 03 00



IEC 60749-23

Edition 1.1 2011-03

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INTERNATIONAL
ELECTROTECHNICAL
COMMISSION

COMMISSION
ELECTROTECHNIQUE
INTERNATIONALE

PRICE CODE **CC**
CODE PRIX

ICS 31.080.01

ISBN 978-2-88912-415-2

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

**SEMICONDUCTOR DEVICES –
MECHANICAL AND CLIMATIC TEST METHODS –****Part 23: High temperature operating life**

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The technical content is therefore identical to the base edition and its amendment and has been prepared for user convenience. A vertical line in the margin shows where the base publication has been modified by amendment 1. Additions and deletions are displayed in red, with deletions being struck through.

International Standard IEC 60749-23 has been prepared by IEC technical committee 47: Semiconductor devices.

This first edition is based on the IEC/PAS 62189 (2000).

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

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